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Ming Li
Bahram Jalali
Keisuke Goda
Kevin K. Tsia
Editors

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Contents

v	<i>Authors</i>
vii	<i>Symposium Committees</i>
xi	<i>Conference Committee</i>

SIGNAL PROCESSING AND MICROWAVE FREQUENCY MEASUREMENTS BASED ON PHOTONICS

10822 02	Multiple-dimensional photonic measurements based on mapping technology (Invited Paper) [10822-1]
10822 03	A photonic system for broadband microwave measurement (Invited Paper) [10822-2]

REAL-TIME PHOTONIC MEASUREMENTS

10822 0A	A real-time multichannel distributed acoustic sensing system with phase-sensitive optical domain reflectometry technology [10822-9]
----------	--

PHOTONICS-ASSISTED MICROWAVE MEASUREMENT SYSTEMS AND OPTICAL IMAGING

10822 0C	Dual-band LFM radar based on a photonic-assisted de-chirp processing receiver [10822-11]
10822 0D	A scanning near-field optical microscope applied to commercial environmental scanning electron microscopes [10822-12]

HIGH-QUALITY SIGNAL GENERATION AND OTHERS

10822 0F	Photonic enabled RF self-interference cancellation for full-duplex communication (Invited Paper) [10822-14]
10822 0G	High-quality microwave generation and frequency up-conversion by photonic integrated two-section DFB lasers [10822-15]
10822 0H	Optical frequency comb generator based on interference among parallel phase modulators [10822-16]

10822 OJ **Particle classification based on polarized light scattering and machine learning** [10822-19]

10822 OK **A tunable self-mixing laser based on frequency electro-optical modulation** [10822-20]

POSTER SESSION

10822 OL **A real-time continuous auto-focus algorithm for stereo microscope cameras** [10822-21]

10822 OO **A Ka-band ultra-wideband microwave photonic imaging radar demonstrator** [10822-24]

10822 OQ **A simulation method for dual-comb spectroscopy with jitter noise** [10822-26]

10822 OS **Sagnac interferometer with polarization maintaining fiber for vector transversal loading measurement** [10822-28]

10822 OU **A fast human action recognition algorithm based on key frame pinning** [10822-30]

10822 OV **A super-resolution reconstruction algorithm of infrared pedestrian images via compressed sensing** [10822-31]

10822 OW **Optical modulation format recognition for polarization-multiplexed coherent system using Chinese restaurant process** [10822-32]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Cao, Jiming, 0C	Wen, Jun, 0H
Chen, Sirui, 0J	Wo, Jianghai, 0O
Chen, Xiangfei, 0G	Wu, Beilei, 0W
Chen, Xinying, 0S	Wu, Guanhao, 0Q
Cong, Wenshan, 0O	Wu, Rui, 0S
Dai, Guanghua, 0O	Xie, Liang, 0D
Ding, Hongyan, 0L	Xu, Tuanwei, 0A
Dong, Jianji, 02	Xu, Yin, 0U
Feng, Shengwen, 0A	Yan, Haitao, 0K
Fermann, Martin E., 03	Yan, Zhi, 0K
Fu, Hongyan, 0S	Yang, Huixia, 0D
Gong, Ping, 0D	Yang, Jiyao, 0C
Guo, Yuxiao, 0W	Yang, Shangwu, 0S
Han, Daofu, 0K	Yu, Feihong, 0L
Han, Xiuyou, 0F	Yu, Haoyang, 0Q
He, Yonghong, 0J	Yu, Lan, 0O
Jian, Shuisheng, 0W	Yu, Yarong, 0K
Jiang, Wen, 0C	Yun, Jin, 0S
Jing, Nan, 0V	Zeng, Jie, 0G
Kuse, Naoya, 03	Zeng, Nan, 0J
Lei, Bo, 0U, 0V	Zhan, Dongjian, 0J
Li, Fang, 0A	Zhang, Jin, 0O
Li, Fei, 0A	Zhang, Junkai, 0O
Li, Ming, 0H	Zhang, Xiangpeng, 0C
Li, Ruoming, 0C	Zhang, Xinliang, 02
Li, Wangzhe, 0C	Zhang, Yunshan, 0G
Li, Wei, 0H	Zhao, Biao, 0O
Li, Xinghui, 0Q	Zhao, Mingshan, 0F
Li, Yihan, 03	Zhou, Hailong, 02
Liu, Weisheng, 0S	Zhou, Qian, 0Q
Lu, Zuye, 0G	Zhou, Rui, 0L
Luo, Xiong, 0O	Zhou, Yuke, 0G
Ma, Hui, 0J	Zhu, Ning Hua, 0H
Ma, Lilong, 0A	Zhu, Yong, 0O
Mo, Zhenwei, 0C	Zou, Erbo, 0V
Mu, Hongqian, 0W	Zou, Linjie, 0G
Mu, Xuejie, 0K	
Ni, Kai, 0Q	
Shao, Yuchen, 0F	
Shi, Yuechun, 0G	
Su, Xinxin, 0F	
Sun, Gangbo, 0U	
Sun, Mengji, 0W	
Tan, Hai, 0U, 0V	
Wang, Anle, 0O	
Wang, Chao, 0F	
Wang, Hanqiao, 0F	
Wang, Muguang, 0W	
Wang, Shuo, 0F	

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- 4 High-Quality Signal Generation and Others
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